



STIC Search Report

EIC 2800

STIC Database Tracking Number: 133639

**TO: Sheila Clark
Location: JEF 6D65
Art Unit : 2815
Monday, September 27, 2004**

Case Serial Number: 10/699021

**From: Irina Speckhard
Location: EIC 2800 JEF 4B59
Phone: (571) 272-2554
irina.speckhard@uspto.gov**

Search Notes

27/2004

10/699,021

S39 0 S38 NOT S18
S40 4408 S10 AND S11
S41 1 S40 AND S12
S42 4407 S40 NOT S41
S43 317 S42 AND S6
S44 141 S43 AND S8
S45 12 S44 AND S9
S46 12 RD (unique items)

Set	Items	Description
S1	2682127	SEMICONDUCT?
S2	1446848	(INTEGRAT????????(3N) (CIRCUIT???????? OR LOOP? ?)) OR IC OR CHIP? ?
S3	204120	CLOS????????(3N) (CIRCUIT???????? OR LOOP? ? OR PATH? ? OR - ROUTE? ? OR ELECTRODE? ?)
S4	3849897	MICRO() (ELECTRONIC? OR CIRCUIT? ? OR CHIP? ?) OR CHIP? ? OR MICROCIRCUIT? ? OR DIE? ? OR LOGIC(W)CIRCUIT? ? OR WAFER? ? - OR MICROELECTRONIC OR DICE OR ELECTROD?
S5	145031	MC=(U11-D01A OR U13-D02 OR U13-D02A) OR IC=(H01L-023/12 OR H01L-027/085 OR H01L-027/088 OR H01L-027/092) OR CC=(B2220 OR B2570)
S6	4755652	S2:S5
S7	315552	(PARTICL? OR MICROPARTICL? OR PARTICULAT? OR DUST? OR GRIT? OR GRAIN? OR GRANUL? OR POWDER? OR SOOT? OR SMUT?) (3N) (SUSPE- N? OR DISPERS? OR COLLOID? OR EMULS? OR MICROEMULS? OR SLURR?)
S8	131284	(PARTICL? OR MICROPARTICL? OR PARTICULAT? OR DUST? OR GRIT? OR GRAIN? OR GRANUL? OR POWDER? OR SOOT? OR SMUT?) (3N) (ASSEM- BL? OR BUNDL? OR GATHER? OR INGATHER? OR GROUP? OR AGGROUP? OR COLLECT? OR BUNCH? OR CROP?)
S9	100983	(PARTICL? OR MICROPARTICL? OR PARTICULAT? OR DUST? OR GRIT? OR GRAIN? OR GRANUL? OR POWDER? OR SOOT? OR SMUT?) (3N) (CLUST- ER? OR CLUMP? OR PACK? OR AMASS? OR ACCUMULAT? OR AGGREGAT? OR (BRING? OR BROUGHT? OR DRAW? OR LUMP? OR BATCH?) (W) ...
S10	228018	S8:S9
S11	198617	(SUSPEN? OR DISPERS? OR COLLOID? OR EMULS? OR MICROEMULS? - OR SLURR?) (3N) (SOLUTION? OR SOLN????? OR SOLVENT? OR RESOLVEN- T? OR RESOLUTIV? OR DILUENT? OR ELUENT? OR LIQUED? OR ALKAHES- T? OR DISSOL? OR SOLUBILIZ? OR SOLUBILIS? OR FLUX? OR ...
S12	19862	DAMAG?(3N) (REGION? OR AREA?)
S13	762050	S1 AND S6
S14	2359	S13 AND S7
S15	126	S14 AND S10
S16	23	S15 AND S11
S17	0	S16 AND S12
S18	21	RD 'S16 (unique items)
S19	103	S15 NOT S16
S20	48	S19 AND S8
S21	1	S20 AND S9
S22	47	S20 NOT S21
S23	14	S22 AND S2
S24	14	RD (unique items)
S25	33	S22 NOT S23
S26	0	S25 AND S3
S27	32	S25 AND S4
S28	29	RD (unique items)
S29	900	S13 AND S11
S30	0	S29 AND S12
S31	33	S29 AND S10
S32	23	S31 AND S7
S33	21	RD (unique items)
S34	0	S33 NOT S18
S35	11	S31 AND S8
S36	3	S35 NOT S18
S37	3	RD (unique items)
S38	8	S35 NOT S36

L Number	Hits	Search Text	DB
3	1	semiconductor adj3 particles adj3 damage	USPAT
4	1	semiconductor adj3 particles adj3 damage	USPAT; US-PGPUB; EPO; JPO
5	3848964	particle adj suspension adj solution	USPAT; US-PGPUB; EPO; JPO
6	8	particle adj suspension adj solution	USPAT; US-PGPUB; EPO; JPO
7	10853	semiconductor and particles and damage	USPAT
8	998	(semiconductor and particles and damage) and accumulation	USPAT
9	22	semiconductor and (particle adj accumulation) and damage	USPAT
10	8	semiconductor and (particle adj accumulation) and damage	US-PGPUB; EPO; JPO
11	1	chip adj3 particles adj3 damage	USPAT; US-PGPUB; EPO; JPO
12	7	die adj3 particles adj3 damage	USPAT; US-PGPUB; EPO; JPO
14	6	(chip and damage and electrolyte and particles) and (particles adj suspended)	USPAT
15	8	semiconductor and particles and (damage adj detector)	USPAT; US-PGPUB; EPO; JPO
16	41	semiconductor and particles and fluid and (particle adj accumulation)	USPAT; US-PGPUB; EPO; JPO
17	57	semiconductor and (damage adj detector)	USPAT; US-PGPUB; EPO; JPO
19	3	(particle adj suspension adj fluid) and damage	USPAT
18	31	particle adj suspension adj fluid	USPAT; US-PGPUB; EPO; JPO
13	220	chip and damage and electrolyte and particles	USPAT
21	2	chip and damage and (electrolyte adj2 particles)	USPAT
22	0	particles adj used adj to adj detect adj defects	USPAT
23	0	particles adj2 to adj detect adj defects	USPAT
24	4	particles adj3 detect adj3 defects	USPAT

25	8	257/\$.ccls. and (particle adj suspension)	USPAT
26	14	257/\$.ccls. and (particle adj2 fluid)	USPAT
27	12	257/\$.ccls. and (particle adj2 accumulation)	USPAT
28	2	257/\$.ccls. and (particulate adj2 accumulation)	USPAT
29	5	438/\$.ccls. and (particulate adj2 accumulation)	USPAT
30	4	438/\$.ccls. and (particle adj2 fluid)	USPAT
31	6	438/\$.ccls. and (particle adj suspension)	USPAT
32	0	438/\$.ccls. and particle and (damage adj detector)	USPAT
33	5	257/\$.ccls. and (particulate adj2 accumulation)	USPAT; US-PGPUB; EPO
34	18	257/\$.ccls. and (particle adj2 accumulation)	USPAT; US-PGPUB; EPO; JPO
20	13044	semiconductor and particles and defects	USPAT; US-PGPUB; EPO; JPO

Ref #	Hits	Search Query	DBs
L1	26	257/48.cccls. and particle	USPAT
L2	163	257/48.cccls. and damage	USPAT
L3	22	2 and solution	USPAT
L4	1	3 and particles	USPAT
L6	7912	"257"/\$.cccls. and (particle suspension adj solution)	USPAT
L7	0	"257"/\$.cccls. and (particle adj suspension adj solution)	USPAT
L8	44	"257"/\$.cccls. and (particle adj2 solution)	USPAT
L9	0	8 and damage	USPAT
L10	15	8 and damage	USPAT